

Search Notes

Application/Control No.

10/658,712

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

YAMADA ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	22,27,29 25,30,32 40,77,82	3/17/2005	<i>SWH</i> SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR